

NOTES FROM READING
 HANDBOOK ON RFI VOL 3 FREDRICK RES. CORP 1962
 MARTIN ISRAEL

GENERAL.

SOLID COVER MUCH BETTER THAN MESH
 FOR HIGH FREQ SHIELD MUST BE ALMOST WATERTIGHT
 USE MULTIPLE SHIELDING & FILTERS FOR ALL LEADS
 BELOW SEVERAL MC COPPER MUST BE VERY THICK FOR MAGNETIC SHIELDING. BETTER TO USE HIGH μ MATERIAL
 ELECTROSTATIC SHIELDING IMPORTANT FOR HIGH VOLTAGES

REFLECTION & ABSORPTION LOSSES IN SHIELDS

1) PLANE WAVE ON INFINITE PLANE SHIELD NORMAL INCIDENCE (WORST CASE)
 (P 3-11) TOTAL LOSS (db) = $\underbrace{3.34 \sqrt{f_m \mu_r \sigma_r S}}_{\text{ABSORPTION}} + 108.2 + \underbrace{10 \log \frac{\sigma_r}{f_m \mu_r}}_{\text{REFLECTION}}$

WHERE f_m = FREQ IN MC
 μ_r = REL. PERM. ($\mu_r = 1$ FOR NON-MAGNETIC)
 σ_r = REL. CONDUCTIVITY ($\sigma_r = 1$ FOR COPPER)
 S = SHIELD THICKNESS IN MILS *

~~AT~~ AT FREQUENCIES ≥ 1 MC MAGNETIC MATERIAL IS BETTER THAN COPPER
~~FOR~~ (BUT EVEN 5 MILS OF CU GIVE 125db)
 (FOR 5 MIL CU ABSORPTION DOMINATES FOR $f > 40$ MC
 FOR 5 MIL $\sigma = 0.1 \mu = 1000$ " " " $f > 0.2$ MC

2) CYLINDRICAL SHIELDS ABOUT LINE OR LOAD SOURCE
 FOR ONE POLARIZATION, REFLECTION PRODUCES LITTLE LOSS
 \therefore CONSIDER ONLY ABSORPTION LOSSES.
 PLANE WAVE EQN GIVES GOOD APPROX.

(NOTE, AT ALL FREQ ~~AT~~ ABSORPTION LOSS FOR TYPICAL MAG SHIELD IS BETTER THAN CU, * BUT FOR 5 MIL CU. ABSORPTION IS FAIRLY LARGE ABOVE

5 MILS CU:

F (MC)	1	10	100	300
ABS. LOSS (DB)	20	50	160	300

* BUT FOR TYPICAL MATERIAL
 σ_r (STEEL) = 0.03 - 0.16
 σ_r (AL) = 0.6
 σ_r (Cu) = 1.0

$\frac{\mu_r}{\mu_0} \frac{\sigma_r}{\sigma_0}$ | ≤ 10 | 100 | 1000 | 10,000
 | 1000 | 100 | 10 | 1
 FOR ABSORP. ADVANTAGE/THICKNESS $(\mu_r \sigma_r)_{\text{steel}} > 1$
 FOR ABSORP. ADVANTAGE/WEIGHT $(\mu_r \sigma_r)_{\text{steel}} > \frac{\rho_{\text{Cu}}}{\rho_{\text{steel}}}$
 (DENSITY OF STEEL ≈ 7.8)
 " " AL ≈ 2.7
 " " Cu ≈ 8.9
 \therefore STEEL BETTER FOR $f_m < 200-1000$

(P3-22)

SHIELDING MATERIALS

MINIMUM THICKNESS OF SOLID WALL FOR 33db ^(IE 100db AT 10 Mc) ABSORPTION LOSS AT 1 Mc

MATERIAL	AL	BRASS	CU	AG	STEEL*	SN
THICKNESS (MILS)	13	20	10	10	25-55	26

* ASSUMING $\mu=1$

PRINCIPLE SHIELDING OF MESH IS DUE TO REFLECTION (ABSORPTION, MUCH LOWER THAN FOR SOLID SHIELD)

TOTAL LOSS OF SOLID WALL INCREASES WITH ^{INCR.} FREQ

BUT " " " MESH DECREASES " " "

(FOR MESH REFLECTION \approx SOLID REFLECTION

$\approx 50\%$ OPEN ≈ 60 STRANDS / WAVELENGTH, PERMANENT ELECT. CONTACT AT INTERSECTIONS)

(P3-24)

HOLES

FOR DIMENSIONS ^{OF HOLE} SMALL COMPARED TO WAVELENGTH, LEAKAGE SMALL, PROPORTIONAL TO HOLE AREA. - MANY SMALL HOLES BETTER THAN ONE LARGE HOLE

[NOTE 10 KMc \leftrightarrow 3 CM. WAVELENGTH \leftrightarrow .03 NSEC RISE TIME]

PROTRUDING SLEEVES AROUND HOLES ACT LIKE WAVEGUIDES PROVIDED LENGTH $\geq 3 \times$ DIAM (OR $3 \times$ LONGEST XSECTIONAL DIMENSION)

$$f_c = \frac{5900}{b}$$

$$f_c = \frac{6920}{d}$$

CUTOFF FOR RECTANG.

CUTOFF FOR CIRCULAR

f_c IN Mc

$b =$ LONGEST ^{XSECTION} DIMENSION IN INCHES

$d =$ DIAM. IN INCHES

NOTE 1" DIAM $\Rightarrow f_c = 6.9$ KMc

.2" DIAM $\Rightarrow f_c = 35$ KMc

FOR $f \leq .1 f_c$ ATEN (db/in) = $\frac{27.3}{b}$ OR $\frac{32}{d}$

SO 1" DIAM $\times 3"$ LONG \Rightarrow

[NOTE: IF A CONDUCTOR RUNS INSIDE THE "WAVEGUIDE" THEN A TEM MODE OF PROPAGATION IS POSSIBLE. THIS MODE HAS NO LOWER FREQ CUTOFF. (IE YOU CAN TRANSMIT DC DOWN A COAX)]

P 3-27

JOINTS : KNITTED MESH IS GOOD [EG. METEX, TECH MITE]
(ALSO LISTS OTHER POSSIBILITIES & CONSIDERATIONS)

SOLDER HAS CONDUCTIVITY ≤ 0.12 OF COPPER
[COMPARE: AL 0.61] SO EVEN A GOOD SOLDER
JOINT IS NOT AS GOOD AS A WELD.

(P 3-44)

CONDUIT RIGID CONDUIT .022" AL \Rightarrow 57 db ABSORPTION AT 1 MC
570 100 MC

FLEXIBLE CONDUIT NOT AS GOOD
TIGHTLY WOVEN BRAID OVER FLEXIBLE CONDUIT GIVES
 ~ 45 db ADDITIONAL ATTEN (AT MOST FREQ)

(P. 6-8)

MISC : GROUND CABLE SHIELDS, COAXIAL FEED THROUGHs, & FILTERS
AT SHIELDS AT POINT OF EXIT OR POINT OF ENTRY

AT HIGH FREQ A GND LEAD WHICH HAS LENGTH
WHICH IS AN ODD MULTIPLE OF $\frac{1}{4}$ WAVELENGTH
MAY HAVE VERY HIGH IMPEDANCE TO GND

AND HIGH IMPEDANCE IN GND LEAD MAY BE CAUSED
BY SUDDEN CHANGES IN CONFIGURATION, AS WHEN
LEAVING A METAL DUCT OR OTHERWISE CHANGING
THE ELECTRICAL RELATIONSHIP TO METALLIC
BODIES. SUCH CHANGES PRODUCE SERIOUS REACTIVE
MISMATCHES